



IEEE 4th International Conference on Computing and Machine
Intelligence
April 05-06, 2025
Central Michigan University

CERTIFICATE

of Participation

This certificate is presented to
Md Tarekul Islam

**For participating and presenting the
paper titled:**

**Classification and Prediction of Wafer Yield Using
Gradient Boosting Algorithms: A focus on
Lithography inline parameters**

A handwritten signature in blue ink, appearing to be "Ah".

General Chair
Ahmed Abdelgawad, PhD